

Notice of References Cited

Application/Control No.

10/815,972

Applicant(s)/Patent Under
Reexamination
NISHII ET AL.

Examiner

Hai H. Huynh

Art Unit

3747

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,632,244	05-1997	Endres et al.	123/306
	B	US-6,615,789 B2	09-2003	Inoue et al.	123/193.6
	C	US-6,705,279 B2	03-2004	Iriya, Yuuichi	123/301
	D	US-6,742,495 B2	06-2004	Ashida et al.	123/310
	E	US-6,745,743 B2	06-2004	Abo et al.	123/295
	F	US-6,748,919 B2	06-2004	Abo et al.	123/299
	G	US-2002/0050266 A1	05-2002	Okamoto et al.	123/298
	H	US-2004/0066297 A1	04-2004	Sakai et al. <i>duplicate</i>	123/308
	I	US-2004/0159314 A1	08-2004	Ishizuka et al.	123/572
	J	US-2004/0065296 A1	04-2004	Arimatsu et al. <i>duplicate</i>	123/308
	K	US-US 20040206343A1	10-2004	Oota et al	123/572
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-124836	04-2004	Japan	Arimatsu et al	F02B-31/00
	O	JP-264816	09-1994	Japan	Takahashi	F02F-01/42
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.